

10/820,632

Substitute form 1449/APTO

INFORMATION DISCLOSURE
STATEMENT BY APPLICANT

(use as many sheets as necessary)

Sheet 1 of 1



Complete if Known

Application Number	10/820,632
Filing Date	April 8, 2004
First Named Inventor	Robin Pierce Gardner
Group Art Unit	2882 2884
Examiner Name	DAVID S. BAKER
Attorney Docket Number	5051-631

U.S. PATENTS AND PATENT PUBLICATIONS

Examiner Initials*	Cite No.	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY
		Number	Kind Code (if known)		
DEB	1.	US-2,922,331	A	Bonner et al.	07-11-1961
DEB	2.	US-2,946,888	A	Scherbatskoy	07-26-1960
DEB	3.	US-3,041,454	A	Baker et al.	06-26-1962
DEB	4.	US-3,041,455	A	Meyerhof	06-26-1962
DEB	5.	US-4,841,153	A	Wormald	06-20-1989
		US-			

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No.	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Translation
		Office	Number	Kind Code (if known)			
DEB	6.	GB	1 000 044	A	Hoesch AG	08-04-1965	

OTHER NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T
DEB	7.	Ember et al. "Coincidence Measurement Setup for PGAA and Nuclear Structure Studies" <i>Applied Radiation and Isotopes</i> 57(4): 573-577 (2002)	
DEB	8.	Ember et al. "Improvement of the Capabilities of PGAA by Coincidence Techniques" <i>Applied Radiation and Isotopes</i> 56(3): 535-541 (2002)	
DEB	9.	International Search Report and Written Opinion of the International Searching Authority for Application No. PCT/US2004/011666 mailed on April 28, 2005	

Examiner Signature

David S. Baker DAVID S. BAKER

Date Considered

4 April 2006

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.